Patent claims

1. A method of reducing a number of measured variables of a technical system,
   a) in which the measured values are divided into classes in accordance with predefined criteria;
   b) in which the measured values in a class are assessed and measured values whose assessment lies below a predefined first threshold value are screened out;
   c) in which the classes are assessed and a class for which the assessment lies below a predefined second threshold value is screened out.

2. The method as claimed in one of the preceding claims, in which one criterion for the division into classes consists in that, for each class, measured values relating to a predefinition of setting parameters of the technical system are determined.

3. The method as claimed in one of the preceding claims, in which, in one class, measured values relating to a transient process and/or erroneous measured values are determined and screened out.

4. The method as claimed in one of the preceding claims, in which, in a class, the number of measured values is reduced in that at least one representative value for the measured values in the class is determined.

5. The method as claimed in claim 4, in which the representative value is determined as
   a) an average of the measured values in the class, or
   b) a maximum value or a minimum value of the measured values in the class;

c) a median.

6. The method as claimed in one of the preceding claims, in which a class which has fewer than a predefined number of measured values is screened out.

7. The method as claimed in one of the preceding claims, in which, in a class, those measured values which differ from a predefinable value by more than a predefinable threshold value are screened out.

8. The method as claimed in one of the preceding claims, in which the reduced measured values are used for the simulation and/or for the draft design of the technical system.

9. An arrangement for reducing a number of measured values of a technical system,
having a processor unit which is set up in such a way that
a) the measured values are divided into classes in accordance with predefined criteria;
b) measured values in a class can be assessed and measured values whose assessment lies below a predefined first threshold value are screened out;
c) the classes are assessed and a class for which the assessment lies below a predefined second threshold value is screened out.

10. The arrangement as claimed in claim 9, in which the processor unit is set up in such a way that the classes are assessed and a class for which the assessment lies below a predefined second threshold value is screened out.

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